IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

h re the application of:

Group Art Unit: 3723

Saldana et al.

Examiner: Unassigned

Application No: 09/748,708

Atty. Docket No: LAM2421

Filed: December 22, 2000

Date: November 11, 2003

For: POLISHING APPARATUS AND

METHODS HAVING HIGH PROCESSING

WORKLOAD FOR CONTROLLING POLISHING)

PRESSURE APPLIED BY POLISHING HEAD

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, Alexandria, VA 22313-1450, on November 11, 20031

Signed:

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR §§1.56 AND 1.97(c)

Mail Stop: DD

Commissioner for Patents Alexandria, VA 22313-1450

Dear Sir:

The references listed in the attached PTO Form 1449, copies of which are attached, may be material to examination of the above-identified patent application. Applicants submit these references in compliance with their duty of disclosure pursuant to 37 CFR §§1.56 and 1.97. The Examiner is requested to make these references of official record in this application.

This Information Disclosure Statement (IDS) is not to be construed as a representation that a search has been made, that additional information material to the examination of this application does not exist, or that these references indeed constitute prior art.

This Information Disclosure Statement is believed to be filed before the mailing date of a first Office Action on the merits. Accordingly, it is believed that no fees are due in connection with the filing of this Information Disclosure Statement. However, if it is determined that any fees are due, the Commissioner is hereby authorized to charge such fees to Deposit Account 50-0805 (Order No. LAM2P421).

Respectfully submitted,

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Customer No. 25920

Attorney Docket No. LAM2P421

Attorney Docket No: U.S.
LAM2P421 10/607,613
Applicant:
Statem nt By Applicant
(Use Several Sheets if Necessary)

Attorney Docket No: U.S.
LAM2P421 10/607,613
Applicant:
Kiermasz et al.
Filing Date: Group:
June 27, 2003 3723

U.S. Patent Documents

Examiner						Sub-	Filing
Initial	No.	Patent No.	Date	Patentee	Class	class	Date
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	R	EP0920956	06/1999	EPO			x	
	S	JP03259520	11/1991	JPO			1	х
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Other Documents

		Other bocuments
Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	W	
	X	
	Y	
	Z	
Examiner		Date Considered

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Forth 1449 (Modified)	Attorney Docket No: LAM2P421	U.S. 10/607,613
Information Disclosur Stat ment By Applicant	Applicant: Kiermasz et al.	
(Use Several Sheets if Necessary)	Filing Date: June 27, 2003	Group: 3723

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Initial	No.	Patent No.	Date	Patentee	Class	class	Date
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Foreign Patent or Published Foreign Patent Application

Examiner		Document	Publication	Country or		Sub-	Trans	lation
Initial	No.	No.	Date	Patent Office	Class	class	Yes	No
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	M							
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	P							

Other Documents

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Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	R	•
	S	
74	Т	
Examiner	!	Date Considered

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.